TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSIV)

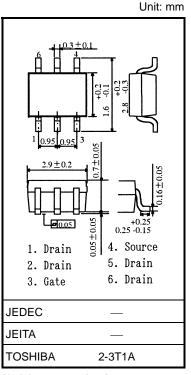
# **TPC6107**

# Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance: RDS (ON) =  $40 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 9.6 \text{ S (typ.)}$
- Low leakage current:  $IDSS = -10 \mu A (max) (VDS = -20 V)$
- Enhancement model:  $V_{th}$  = -0.5 to -1.2 V ( $V_{DS}$  = -10 V,  $I_D$  = -200  $\mu A$ )

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-20	V	
Drain-gate voltage (R <sub>G</sub>	<sub>S</sub> = 20 kΩ)	$V_{DGR}$	-20	V	
Gate-source voltage		$V_{GSS}$	±12	V	
Drain current	DC (Note 1)	I <sub>D</sub>	-4.5	А	
Diam current	Pulse (Note 1)	I <sub>DP</sub>	-18		
Drain power dissipation	(t = 5 s) (Note 2a)	P <sub>D</sub>	2.2	W	
Drain power dissipation (t = 5 s) (Note 2b)		P <sub>D</sub>	0.7	W	
Single pulse avalanche	energy (Note 3)	E <sub>AS</sub>	1.3	mJ	
Avalanche current		I <sub>AR</sub>	-2.25	А	
Repetitive avalanche e	nergy (Note 4)	E <sub>AR</sub>	0.22	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	inge	T <sub>stg</sub>	-55 to 150	°C	



Weight: 0.011 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

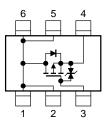
#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	R <sub>th (ch-a)</sub>	56.8	°C/W	
Thermal resistance, channel to ambient $(t = 5 s)$ (Note 2b)	R <sub>th (ch-a)</sub>	178.5	°C/W	

Note: (Note 1), (Note 2), (Note 3), (Note 4) and (Note 5): See the next page.

This transistor is an electrostatic-sensitive device. Please handle with caution.

#### **Circuit Configuration**



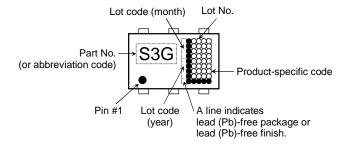
# **Electrical Characteristics (Ta = 25°C)**

Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rent	I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-OFF cu	ırrent	I <sub>DSS</sub>	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-10	μΑ
Drain-source breakdown voltage		V (BR) DSS	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-20	_	_	V
		V (BR) DSX	$I_D = -10 \text{ mA}, V_{GS} = 12 \text{ V}$	-8	_	_	
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, I_D = -200  \mu\text{A}$	-0.5	_	-1.2	٧
Drain-source ON resistance		R <sub>DS</sub> (ON)	$V_{GS} = -2 \text{ V}, I_D = -2.2 \text{ A}$	_	110	180	mΩ
		R <sub>DS</sub> (ON)	$V_{GS} = -2.5 \text{ V}, I_D = -2.2 \text{ A}$	_	70	100	
			$V_{GS} = -4.5 \text{ V}, I_D = -2.2 \text{ A}$	_	40	55	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -2.2 \text{ A}$	4.8	9.6	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	680	_	pF
Reverse transfer capacitance		C <sub>rss</sub>		_	130	_	
Output capacitance		C <sub>oss</sub>		_	140	_	
Switching time	Rise time	t <sub>r</sub>	V <sub>GS</sub> 0 V   I <sub>D</sub> = -2.2 A   V <sub>GS</sub> 0 V   V <sub>G</sub> 0 V <sub>OUT</sub> 0 V <sub>OUT</sub> 0 V <sub>G</sub> 0 V <sub>OUT</sub> 0 V <sub>G</sub> 0 V <sub>G</sub> 0 V <sub>OUT</sub> 0 V <sub>G</sub>	_	6	_	
	Turn-ON time	t <sub>on</sub>		_	16	_	
	Fall time	t <sub>f</sub>		_	38	_	ns
	Turn-OFF time	t <sub>off</sub>	$V_{DD} \simeq -10 \text{ V}$ Duty $\leq 1\%$ , $t_w = 10 \mu\text{s}$	_	85	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -16 \text{ V}, V_{GS} = -5 \text{ V},$ $I_{D} = -4.5 \text{ A}$	_	9.8	_	
Gate-source charge		Q <sub>gs</sub>			2		nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	3	_	

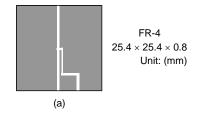
## Source-Drain Ratings and Characteristics (Ta = 25°C)

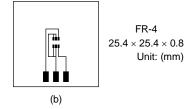
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Pulse drain reverse current (N	Note 1)	I <sub>DRP</sub>	_	_	_	-18	Α
Forward voltage (diode)		$V_{DSF}$	$I_{DR} = -4.5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.2	V

## Marking (Note 5)

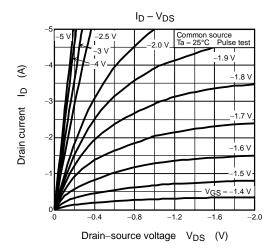


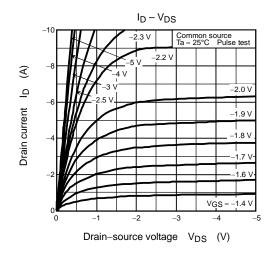
- Note 1: Ensure that the channel temperature does not exceed 150°C.
- Note 2: (a) Device mounted on a glass-epoxy board (a) (t = 5 s)
  - (b) Device mounted on a glass-epoxy board (b) (t = 5 s)

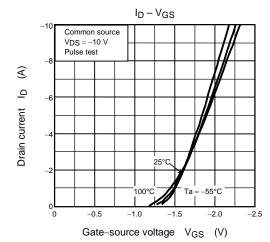


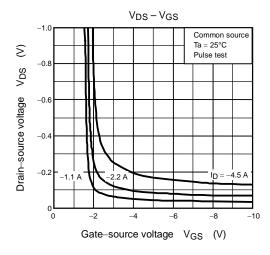


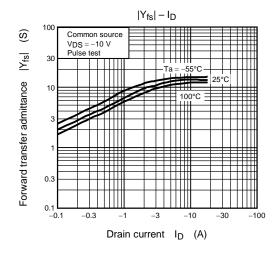
- Note 3: V<sub>DD</sub> = 16 V, T<sub>Ch</sub> = 25°C (initial), L = 0.2 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = -2.25 A
- Note 4: Repetitive rating: pulse width limited by maximum channel temperature
- Note 5: on lower left of the marking indicates Pin 1.

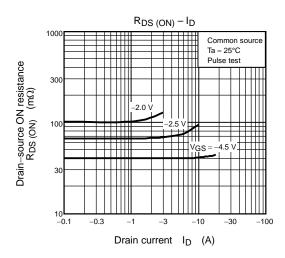




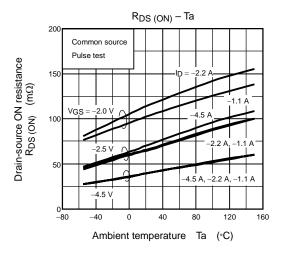


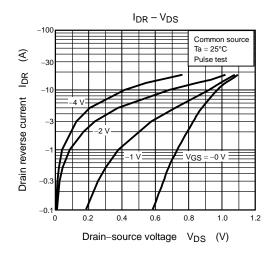


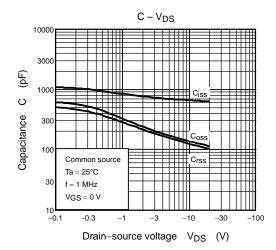


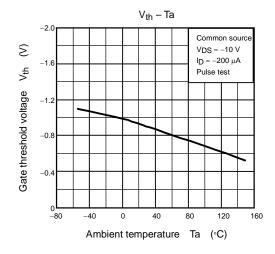


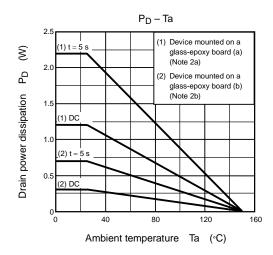
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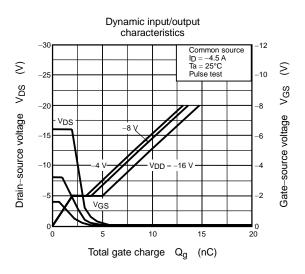


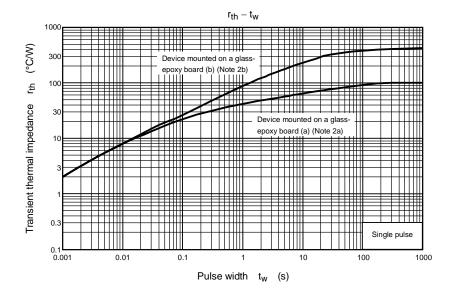


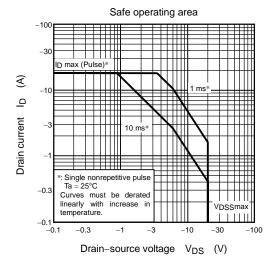












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